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## **Water-soluble and amphiphilic polymers**

### 6. A study on **the sudace** composition of **cast films**  of PSt/PMAA **and PEO-PSt-PEO** block polymers by **XPS**

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### **SUHHARY**

Thin films of PSt/PHAA and PEO-PSt-PEO block polymers were deposited on a polystyrene substrate by solution adsorption ( with<br>or without solvent treatment ), and the film surfaces were or without solvent treatment ) and the film surfaces were characterized by means of XPS. Direct solvent - casting of PEO-PSt-PEO from benzene solutions resulted in PSt-rlch surfaces, whereas PNAA richer surfaces were obtained for PSt/PMAA films cast from DMF solutions. Moreover, solvent treatment after casting had<br>profound effect on the film surface composition. Treatment with effect on the film surface composition. Treatment with water markedly increased the surface concentration of polar PEO segments. In the case of PSt-PNAA block polymers, the PSi content on the surface increased in the order of water < ethanol < cyclohexane < petroleum ether , the last-named giving films with almost pure PSi surface. It is yell worth noticing that the bulk oomposltion had little-to-do with the surface composition for both<br>PSt/PMAA and PEO-PSt-PEO block polymers within-the-composition PSt/PNAA and PEO-PSt-PEO block polymers range investigated when subsequent solvent treatment was applied.

# INTRODUCTION

The surface properties of polymers are essential {n many applications. A knowledge of the chemical composition of the outermost layer is of prime importance for the understanding and prediction of surface properties. A number of techniques have been used to examine polymer surfaces, and along these, X-ray photoelectron spectroscopy (XPS, also called ESCA) has become a valuable tool. XPS analysis provides two types of information about the top 5 nm of the sample surface:(a) the atoms present at the surface and their chemical environment; (b) the stoichiometry of the sample.

Block polymers have been the subject of surface analysis by<br>means of XPS. Clark and Peeling (1) used XPS to study the surface means of XPS. Clark and Peeling (I) used XPS to study the surface co,position of polystyrene( PSt )/poly( dimethylsiloxane ) (PDNS) diblock polymers and found PDNS predominant overlayers. Thomas and

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O'Malley investigated the surfaces of PSt/poly(ethylene oxide) (PEO) CO, ~ X ~'~ - ~c: :~r-',-" ~'~CO ".~ 0 ~r"--~ 0 diblock (2) and triblock (3) polymers, and found that the surface composition of the polymers was higher in PSt than the bulk composition. The important conclusion so far obtained is: the lower surface free energy component will become richer on the surface. This conclusion has been supported by a variety of block polymer systems. including poly (bisphenol A-carbonate) (PC)/PDMS(4-6), PC/polysulfone (PSF) (4), poly (p-hydroxystyrene)/PSF/PDMS (7), urethane (8-11), PEO/poly (pivalolactone) (12), polypeptide/polybutadiene (13) and poly (ethylene terephthalate) / perfluoro polyether (14). The "low free energy component surface enrichment " phenomenom also holds in other multiphase polymer systems, even in ethylene/chlorotrifluoroethylene alternating copolymer (11).

Amphiphilic polymers can be used to improve surface hydrophilicity of hydrophobic polymers, for example PSt. This paper involves a study of the surface composition of polystyrene/poly(methacrylic acid)(PSt/PNAA) and PEO-PSt-PEO block polymers dip-coated on a PSt substrate, and emphasizes the influence of solvent treatment.

# **EXPERIMENTAL**

Materials --- The PSt/PMAA block polymers were prepared - Z 1 Z ∎;i f r r c m a t e y r bу mE CD **c-F -'~ ~e-"3**  radical polymerization by using a polyazoester as an initiator(15). **~U "~I: ~** ~.~"" The synthesis of PEO-PSt-PEO triblock polymers was described in a previous paper (16). A reference PSt homopolymer was synthesized by anionic polymerization by using sodium naphthalene as the initiator. The homo-PMAA sample was obtained by AIBN initiated polymerization. The characteristics of these polymers are given in Table 1.

N, N-dimethylformamide (DMF), ethanol, cyclohexane, petroleum ether and benzene used were A. R. grade solvents. Water was twicedistilled.

t<br>e<br>e<br>c <u>XPS Sample Preparation</u> -- Thin films of PSt/PMAA block polymers<br>were deposited from dilute DMF solutions (C=0.5 g/100 ml, for - **\***  $\frac{1}{6}$  see p<br>p c-i-h c $+$ 0 /<br>e ]<br>a ~ 4-5 sec.) on clean PSt substrates which had been prepared by dip-coating a PSt thin layer from  $a \sim 1$  g/100 ml benzene solution 0<br>.e<br>.i hot-pressed PSt plates (2 mm thick) to preclude oxygen  $0<sub>n</sub>$ on the surface. When solvent treatment contamination vas applied the test specimen was subsequently dipped into a solvent for  $5 \text{ min.}$ 

Pr<br>Pr<br>P50+ **sr**<br>" Films of PEO-PSt-PEO triblock polymers on clean PSt substrates<br>were prepared by dip-coating from benzene solutions (C=1.0 or 0<br>f r<br>"d r:  $0<sub>r</sub>$ 0.5 g/100 ml, for 4-5 sec.), and then followed by three different procedures: (a) without solvent treatment, (b) subsequently treated with water overnight, and (c) dried overnight and then dipped in water overnight.

All test specimens were dried at room temperature in vacuum for at least two days before XPS study.

spectra were recorded on an ESCALAB XPS Measurement --- XPS NkII ("VG" Company") electron spectrometer using Mg -K q <sub>1,2</sub> exciting at 14 kV and 20 mA. radiation.with a X-ray All the XPS gun measurements were made by analyzing the photoemitted-electrons normal to the surface of the samples. The value of 285.0 eV was used for the C<sub>1</sub>, core level of the hydrocarbon. The calculation of C/O ratios was based on the experimental intensity ratios of  $C_{1\alpha}/$   $0_{1\alpha}$ , and the relative photoionization sensitivity (2.97) of  $0_{1}$ ./C<sub>1</sub>. obtained in our laboratory.

# RESULTS AND DISCUSSION

The XPS core level spectra for PSt and PNAA homopolymers are shown in Fig. 1. A clean PSt surface shows a sharp peak from main photonization of the C<sub>1</sub>a level at 285.0 eV, and a broad shake-up satellite at 291.7 eV arising from  $\pi * \leftarrow \pi$  transition in the benzene groups (2, 17). The surface of a clean PSt substrate contains little oxygen. The C<sub>1</sub>, spectrum of PMAA exhibits double-peak structure: the smaller peak at 289.1 eV is easily identified as arising from its carbonyl carbon atoms, the position of which is in good

	Composition	* *)	
Sample	PSt wt%	PSt mol%	$\mathbf{I}$ (n!/g)
(PSt/PMAA) (PSt/PMAA) B (PSt/PNAA) (PMAA) D (PEO-PSt-PEO) E (PEO-PSt-PEO) F (PEO-PSt-PEO) G (PEO-PSt-PEO) H (PSt)	72.3 64.1 41.5 88.2 87.2 58.8 55.7 100	68.3 59.6 37.0 76.0 74.2 37.3 34.7 100	92.0 116.0 167.0 112.0 28.4 27.0 28.4 27.3 30.9

Table 1. Main characteristics of polymer samples

 $\ast$ ) determined by H-NMR

\* \*) measured at 30.0°C in DMF for samples A-D, at 25.0°C in toluene for E-I



Figure I. XPS spectra of PSt and PNAA homopolymers

agreement with the literature data for poly(acrylic acid) (18). The broad peak at  $\sim$  533 eV is contributed by the two carboxyl oxygen atoms in different chemical environments (18).

In Fig. 2, we present the spectra of PSt/PMAA block polymer B, without and with subsequent solvent treatment. The line-shape analysis of the total  $C_{1\bullet}$  envelope (except for that treated with petroleum ether ) reveals the presence of three components at 285.0,<br>289.1, and 291.7 eV, respectively. The calculated surface  $291.7$  eV, respectively. composition data are listed in Table 2.

Sample	PSt at surface $\mathbb{R}^{\{0\}}$					
	no solvent treatment	vater	solvent ethanol	treatment cyclohexane	vith petroleum ether	
B	44.0 46.4 35.6	55.2 50.1 54.8	61.0 63.0	81.9 82.7 87.2	93.1 97.7 98.0	

Table 2. Variation of surface composition of PSt-PHAA films with solvent treatment



It is of interest to note that the subsequent solvent treatment<br>a profound effect on the film surface composition. The PSt conhas a profound effect on the film surface composition.  $\blacksquare$ tent on the surface increases in the order of water < ethanol < cyclohexane < petroleum ether, the last naaed giving films vith almost pure PSt surface. The effect of solvent treatment is in good consistence with the solubility parameter of the solvent used. The more polar the solvent is, the lower the PSt content on the surface.

As previously stated, the conclusion so far drawn is that the lower free energy component always concentrates on the surface of aultiphase polymer systems. This is connected with the polymer-air interface and caused by a thermodynamic reason. segment would tend to transfer towards the surface to reduce the<br>surface energy. The solvent treatment has changed the polymer-air The solvent treatment has changed the polymer-air interface to polymer-solvent (in fact, nonsolvent or precipitant) interface, which may apparently induce changes in the polymer chain arrangeaent to fit the surface energy requirement under the specific interface situation. Non-polar solvents vould favor aoveaent of the lover free energy segments to the polymer surface, vhile the polar solvents vould attract the polar segments tovards the surface.

For similar reason, nature of the solvent used for the cast solution would influence the surface stoichioaetry of the solvent -cast films of aultiphase polymer systeas, lt is interesting to note from the data in Table 2 that we have obtained surfaces richer in higher free energy component PNAA than the bulk by direct solvent-casting from dilute DMF solutions of

polymers.<br>Fig. 3 and Table 3 show the surface composition for PEO-PSt-PEO triblock polymers. Direct casting from benzene solutions results in PSi-rich surfaces, which is very similar with the results obtained by Thomas and O'Halley (2,3) for PEO/PSt di- and tri- block polymers cast from solutions of chloroform which has similar solubility parameter as benzene. Thonas and O'Halley also studied the surface composition of PEO/PSt diblock polymers<br>cast from ethylbenzene, or, nitromethane solutions, (2). It, seems cast from ethylbenzene or nitroaethane solutions (2). It seems that the di- or tri- block structure and the molecular weight don't have apparent influence on the surface composition of the solvent-cast films, which is mainly governed by the bulk compo-<br>sition and the solvent used. Taking PEO/PSt block polymers with sition and the solvent used. Taking PEO/PSt-block-polymers-with the same composition (say, 50 mol  $\frac{1}{2}$  PSt) for comparison and putting the results of Thomas eta]. and ours together in Table 4, we can see that the surface composition of PEO/PSt block polymers is strongly solvent-dependent. The polar solvent favors the enrichment of high free energy segment on the surface.



$Sample \mid$	*)	Procedure**)			
	Conc.	a	b	C	
E	1.0	85.7	59.2	70.8	
	0.5	90.5	61.9	77.1	
F	1.0	83.3	61.7	80.8	
	0.5	90.9	61.7	76.7	
G	1.0	66.8	62.8	60.4	
	0.5	72.5	61.7	68.1	
H	1.0	56.3	64.0	61.9	
	0.5	67.2	53.5	69.6	

Table 3. PSt mole % content on the surface of PEO-PSt-PEO films

\*) g polymer/lO0 ml benzene

\*\*) see the part of experimental

As showm in Fig. 3 and Table 3. water treament markedly increases the concentration of PEO segment on the surface,and water treatment may cause the rearrangement of the PEO/PSt surface after the sample has been *dried.* 

Moreover, it is yell worth notice from Fig. 3 and Table 2 that the composition of the block polymers has little to do vith the surface composition for both PEO-PSt-PEO and PSt/PMAA block polymers vhithin the composition range investigated when subsequent solvent treatment is applied.





\*) Bulk composition is referenced to 50 mo]% of PSt.

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